

FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. TI-14124D.6		SERIAL NO. div. of 10/649,274		
LIST OF DOCUMENTS CITED BY APPLICANT <i>(Use several sheets if necessary)</i>				APPLICANT Lee D. Whetsel				
				FILING DATE October 22, 2003		GROUP TBD 2133		
FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
cb		EP 0,310,152	4/5/1989	Europe	G01	R31/28	X	
		JP 01-038674 A	2/8/1989	Japan	G01R	31/28	X	
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cb		JP 64-006572	1/13/1989	Japan	G01R	31/28	X	
EXAMINER		DATE CONSIDERED						
C. Broth		4-25-08						
+EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

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EXAMINER C. Batt				DATE CONSIDERED 4-25-05	
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